

<b>Notice of References Cited</b>	Application/Control No. 09/873,815		Applicant(s)/Patent Under Reexamination LAVORGNA ET AL.	
	Examiner Tan Dean D. Nguyen		Art Unit 3629	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,684,369	01-2004	Bernardo et al.	715/513
*	B	US-2002/0059264	05-2002	Fleming et al.	707/100
*	C	US-2002/0173997	11-2002	Menard et al.	705/7
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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